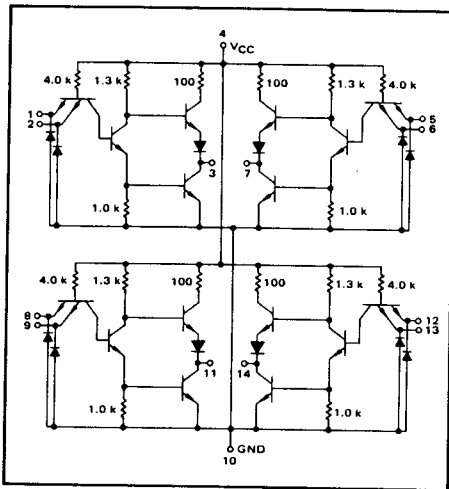


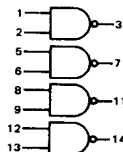
QUAD 2-INPUT "NAND" GATE

MTTL I MC500/400 series

MC508 · MC558  
MC408 · MC458



This device consists of four 2-input NAND gates. The four gates in a single package represent increased functional flexibility. For example, a dual set-reset flip-flop may be obtained if each pair of gates is externally cross-coupled.



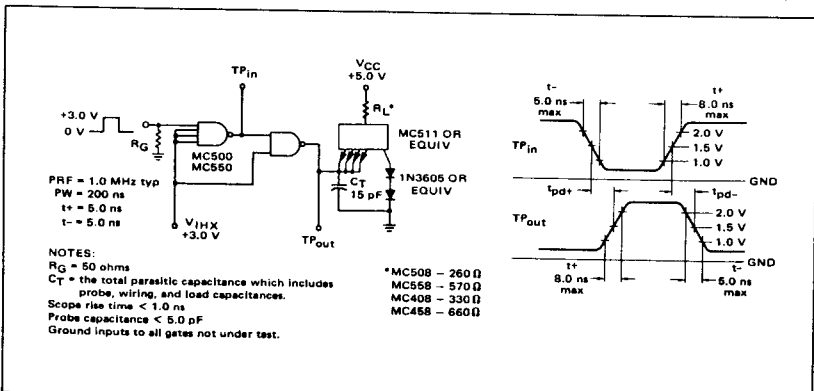
Positive Logic:  $3 = \overline{1 \cdot 2}$   
Negative Logic:  $3 = \overline{1 + 2}$

Total Power Dissipation = 60 mW typ/pkg  
Propagation Delay Time = 10 ns typ

TYPE NO.	INPUT LOADING FACTOR	( $t_f$ )	OUTPUT DRIVE	( $I_{OL}$ )	TEMPERATURE RANGE
MC508	1	(-1.33 mA)	15 MC500 series Gates	(20 mA)	-55°C to +125°C
MC558			7 MC500 series Gates	(10 mA)	
MC408	1	(-1.66 mA)	12 MC400 series Gates	(20 mA)	0° to +75°C
MC458			6 MC400 series Gates	(10 mA)	

SWITCHING TIME TEST CIRCUIT

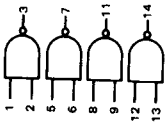
VOLTAGE WAVEFORMS AND DEFINITIONS



MC508, MC558/MC408, MC458 (continued)

ELECTRICAL CHARACTERISTICS

Test procedures are shown for only one gate. The other gates are tested in a similar manner. Further, test procedures are shown for only one input of the gate being tested. The other input is tested in the same manner.



Characteristic	Symbol	MC508, MC558 Test Limits						MC408, MC458 Test Limits						TEST CONDITIONS												
		-55°C		+25°C		+75°C		-55°C		+25°C		+75°C		mA				Volts								
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit	$I_{OL}$	$I_{OH}$	$I_{in}$	$V_{IK}$	$V_{IH}$	$V_{A1}$	$V_{A0}$	$V_{out}$	$V_{CC}$	$V_{ECH}$	$V_{inX}$	
Input																										
Forward Current	$I_F$	1	-1.33	-1.33	-1.33	-1.33	-1.66	-1.66	-1.66	-1.66	-1.66	-1.66	mA													
Leakage Current	$I_L$	1	100	100	100	100	100	100	100	100	100	100	$\mu$ Adc													
Inverse Beta Current	$I_{\beta}$	1	100	100	100	100	100	100	100	100	100	100	$\mu$ Adc													
Breakdown Voltage	$BV_{in}^{(1)}$	1	5.5	5.5	5.5	5.5	5.5	5.5	5.5	5.5	5.5	5.5	Vdc													
Output																										
Output Voltage	$V_{out}^{(2)}$	3	0.45	0.45	0.45	0.45	0.45	0.45	0.45	0.45	0.45	0.45	Vdc													
Leakage Current	$I_{OLK}$	3	2.5	2.4	2.7	2.5	2.4	2.5	2.5	2.5	2.5	2.5	Vdc													
Short-Circuit Current	$I_{SC}$	3	-250	-250	-250	-250	-250	-250	-250	-250	-250	-250	$\mu$ Adc													
Output Voltage	$V_{OL}$	3	0.40	0.40	0.40	0.40	0.40	0.40	0.40	0.40	0.40	0.45	Vdc													
Power Requirements																										
(Total Device) Maximum Power Supply Current	$I_{max}$	4	20	20	20	20	20	20	20	20	20	20	mA													
Power Supply Drain	$I_{DDH}$	4	24	24	24	24	30	30	30	30	30	30	mA													
Switching Parameters																										
Turn-On Delay	$t_{pd}$	1,3	20	20	20	20	20	20	20	20	20	20	ns													
Turn-Off Delay	$t_{pd}^*$	1,3	20	20	20	20	20	20	20	20	20	20	ns													
Rise Time	$t_r^*$	1,3	8.0	8.0	8.0	8.0	8.0	8.0	8.0	8.0	8.0	8.0	ns													
Fall Time	$t_f^*$	1,3	5.0	5.0	5.0	5.0	5.0	5.0	5.0	5.0	5.0	5.0	ns													

\* Pulse Fan-Out: Ground input to gates not under test; during ALL test; unless otherwise noted. \* The figure to all gates must be ungrounded.